

Quality Information for Product Type PMEG100V100ELPD

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Quick reference

Information	Content
Device Type	PMEG100V100ELPD
Ordering Information (12NCs)	9340 695 19139, 9340 695 19146
Qualification Grade	automotive
Package	SOT1289 (CFP15)
Waferfab	Nexperia DHAM, NXP ICN8
Assembly	Nexperia ATSN
ESD HBM	> 4000 V, <= 8000 V
Calculated Failure Rate	0.97 FIT
MTBF/MTTF	1.03E+09 hours

Explanation

Automotive qualified products are in accordance with the AEC-Q101.

Electrostatic Discharge (ESD) tests are performed as described in the AEC-Q101 with each 3 positive and 3 negative pulses for each stress voltage level.

Test considered for FIT calculation: High Temperature Reverse Bias (HTRB, AEC-Q101 Test # 5). The parameters for calculation of FIT and MTBF/MTTF are as follows: Confidence level 60%, junction temperature derated to 55 °C, activation energy 0.7 eV, test time 168 - 1000 hrs.

For discrete semiconductor devices the Mean Time Between Failure (MTBF) is replaced by the Mean Time To Failure (MTTF) acronym. MTTF is calculated from the Intrinsic Failure Rate.